

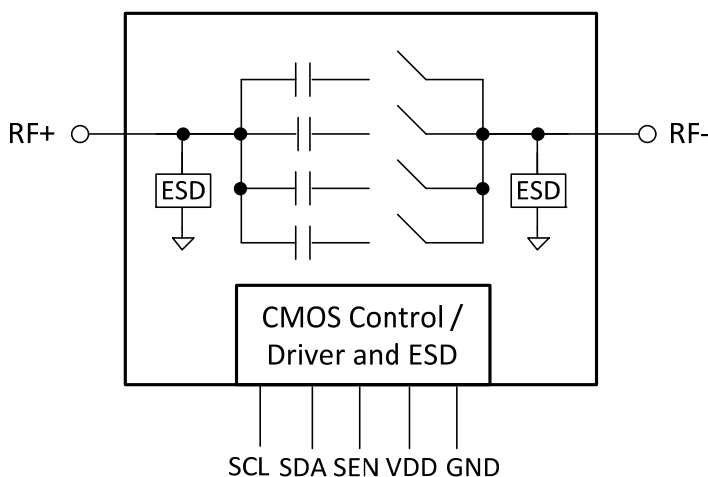
Product Description

PE623090 is a DuNE™-enhanced Digitally Tunable Capacitor (DTC) based on Peregrine’s UltraCMOS® technology. This highly versatile product supports a wide variety of tuning circuit topologies with emphasis on impedance matching and aperture tuning applications. PE623090 is optimized for key cellular frequency bands from 700 to 2700 MHz.

PE623090 offers high RF power handling and ruggedness while meeting challenging harmonic and linearity requirements enabled by Peregrine’s HaRP™ technology. The device is controlled through the widely supported 3-wire (SPI compatible) interface. All decoding and biasing is integrated on-chip and no external bypassing or filtering components are required.

DuNE™ devices feature ease of use while delivering superior RF performance in the form of tuning accuracy, monotonicity, tuning ratio, power handling, size, and quality factor. With built-in bias voltage generation and ESD protection, DTC products provide a monolithically integrated tuning solution for demanding RF applications.

Figure 1. Functional Block Diagram



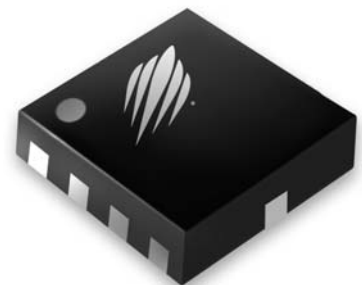
UltraCMOS® Digitally Tunable Capacitor (DTC) Optimized for 2G/3G/4G Tuning Applications, 100-3000 MHz

Features

- 4-bit 16-state Digitally Tunable Capacitor
- Shunt configuration $C = 0.6$ to 2.35 pF (3.9:1 tuning ratio) in discrete 117 fF steps
- High RF power handling ($30 V_{pk}$ RF) and linearity for 2G/3G/4G applications
- Wide power supply range (2.3 to 4.8V) for operation from V_{BATT}
- $2 \times 2 \times 0.55$ mm QFN package
- High ESD tolerance of 2kV HBM on all pins
- Applications include:
 - Open and closed-loop Tunable Antennas for 2G/3G/4G
 - Tunable Matching Networks
 - Tunable Filter Networks

Figure 2. Package Type

10-lead $2 \times 2 \times 0.55$ mm QFN package



**Table 1. Electrical Specifications @ 25 °C, V_{DD} = 2.75V
(In shunt configuration, RF- connected to GND)**

| Parameter | Condition | Min | Typ | Max | Unit |
|---|--|------|------------|------|------|
| Operating Frequency Range | | 100 | | 3000 | MHz |
| Minimum Capacitance (C _{min}) | State 0000, 100 MHz | 0.54 | 0.60 | 0.66 | pF |
| Maximum Capacitance (C _{max}) | State 1111, 100 MHz | 2.11 | 2.35 | 2.59 | pF |
| Tuning Ratio | C _{max} /C _{min} , 100 MHz | | 3.9:1 | | |
| Step Size | 4 bits (16 states), 100 MHz | | 0.117 | | pF |
| Quality Factor (C _{min}) ¹ | 698 to 960 MHz, with L _S removed 1710 to 2170 MHz, with L _S removed | | 40 40 | | |
| Quality Factor (C _{max}) ¹ | 698 to 960 MHz, with L _S removed 1710 to 2170 MHz, with L _S removed | | 29 13 | | |
| Self Resonant Frequency | State 0000 State 1111 | | 9.1 3.7 | | GHz |
| Harmonics ² | 2fo: 698 to 915 MHz; Pin +34 dBm, 50 Ω | | -40 | -36 | dBm |
| | 3fo: 698 to 915 MHz; Pin +34 dBm, 50 Ω | | -50 | -36 | dBm |
| | 2fo: 1710 to 1910 MHz; Pin +32 dBm, 50 Ω | | -40 | -36 | dBm |
| | 3fo: 1710 to 1910 MHz; Pin +32 dBm, 50 Ω | | -50 | -36 | dBm |
| IMD3 | Bands I,II,V/VIII, +20 dBm CW @ TX freq, -15 dBm CW @ 2Tx-Rx freq, 50 Ω | | -115 | -105 | dBm |
| Switching Time ^{3,4} | State change to 10/90% delta capacitance between any two adjacent states | | | 12 | μs |
| Start-up Time ³ | Time from V _{DD} within specification to all performances within specification | | | 70 | μs |
| Wake-up Time ^{3,4} | State change from Standby mode to RF state to all performances within specification | | | 70 | μs |

Notes: 1. Q for a Shunt DTC based on a Series RLC equivalent circuit

$Q = X_C/R = (X-X_L)/R$, where $X = X_L+X_C$, $X_L = 2\pi fL$, $X_C = -1/(2\pi fC)$, which is equal to removing the effect of parasitic inductance L_S

2. In Shunt between 50 Ω ports. Pulsed RF input with 4620 μS period, 50% duty cycle, measured per 3GPP TS 45.005

3. DC path to ground at RF- must be provided to achieve specified performance

4. State change activated on falling edge of SEN following data word

Figure 3. Pin Configuration (Top View)

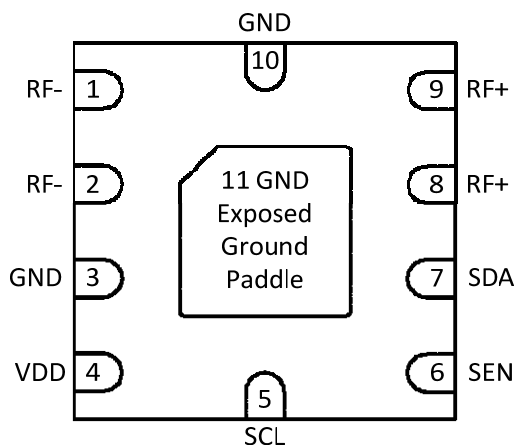


Table 2. Pin Descriptions

| Pin # | Pin Name | Description |
|-------|-----------------|-------------------------------------|
| 1 | RF- | Negative RF Port ¹ |
| 2 | RF- | Negative RF Port ¹ |
| 3 | GND | Ground ² |
| 4 | V _{DD} | Supply |
| 5 | SCL | Serial Interface Clock Input |
| 6 | SEN | Serial Interface Latch Enable Input |
| 7 | SDA | Serial Interface Data Input |
| 8 | RF+ | Positive RF Port ¹ |
| 9 | RF+ | Positive RF Port ¹ |
| 10 | GND | Ground ² |
| 11 | GND | Exposed Ground Paddle ² |

Notes: 1. Multiple RF pins are provided for flexibility. They can be tied together for optimal RF performance, or used individually (leave unused pin floating)
 2. For optimal performance, recommend tying Pins 3, 10, and 11 together on PCB

Moisture Sensitivity Level

The Moisture Sensitivity Level rating for the PE623090 in the 10-lead 2 x 2 x 0.55 mm QFN package is MSL1.

Table 3. Operating Ranges

| Parameter | Min | Typ | Max | Units |
|---|-----|------|------------|------------------------------------|
| V _{DD} Supply Voltage | 2.3 | 2.75 | 4.8 | V |
| I _{DD} Power Supply Current (V _{DD} = 2.75V) | | 140 | 200 | μA |
| I _{DD} Standby Current (V _{DD} = 2.75V) | | 25 | | μA |
| V _{IH} Control Voltage High | 1.2 | 1.8 | 3.1 | V |
| V _{IL} Control Voltage Low | 0 | 0 | 0.57 | V |
| RF Input Power (50 Ω) ¹ 698 to 915 MHz 1710 to 1910 MHz | | | +34 +32 | dBm dBm |
| Peak Operating RF Voltage ² V _P to V _M V _P to RFGND | | | 30 30 | V _{pk} V _{pk} |
| T _{OP} Operating Temperature Range | -40 | +25 | +85 | °C |
| T _{ST} Storage Temperature Range | -65 | +25 | +150 | °C |

Notes: 1. Maximum power available from 50 Ω source. Pulsed RF input with 4620 μS period, 50% duty cycle, measured per 3GPP TS 45.005 measured in shunt between 50 Ω ports, RF- connected to GND
 2. Node voltages defined per Equivalent Circuit Model Schematic (Figure 12). Refer to page 7 if using DTC in series configuration

Table 4. Absolute Maximum Ratings

| Symbol | Parameter/Conditions | Min | Max | Units |
|------------------|--|-----|------|-------|
| V _{ESD} | ESD Voltage (HBM, MIL_STD 883 Method 3015.7), all pins | | 2000 | V |

Exceeding absolute maximum ratings may cause permanent damage. Operation should be restricted to the limits in the Operating Ranges table. Operation between operating range maximum and absolute maximum for extended periods may reduce reliability.

Electrostatic Discharge (ESD) Precautions

When handling this UltraCMOS[®] device, observe the same precautions that you would use with other ESD-sensitive devices. Although this device contains circuitry to protect it from damage due to ESD, precautions should be taken to avoid exceeding the specified rating.

Latch-Up Avoidance

Unlike conventional CMOS devices, UltraCMOS[®] devices are immune to latch-up.

Performance Plots @ 25°C and 2.75V unless otherwise specified

Figure 4. Measured Shunt C (@ 100 MHz) vs State

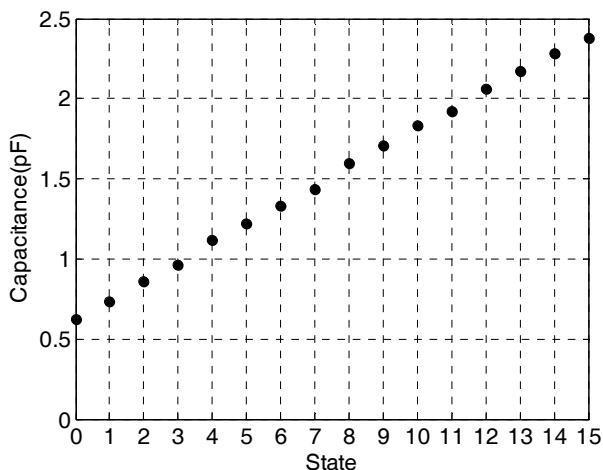


Figure 5. Measured Shunt S₁₁ (major states)

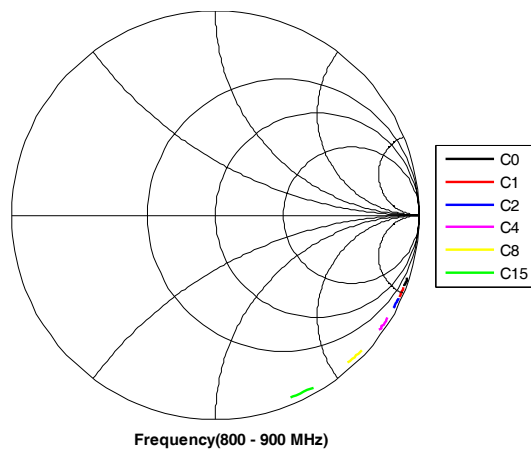


Figure 6. Measured Step Size vs State (frequency)

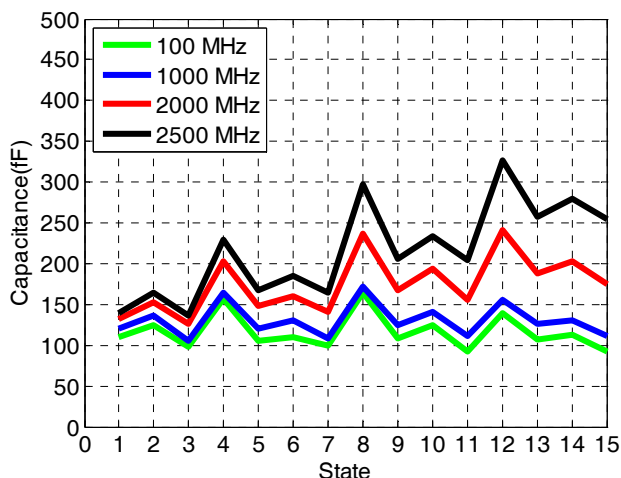


Figure 7. Measured Series S₁₁/S₂₂ (major states)

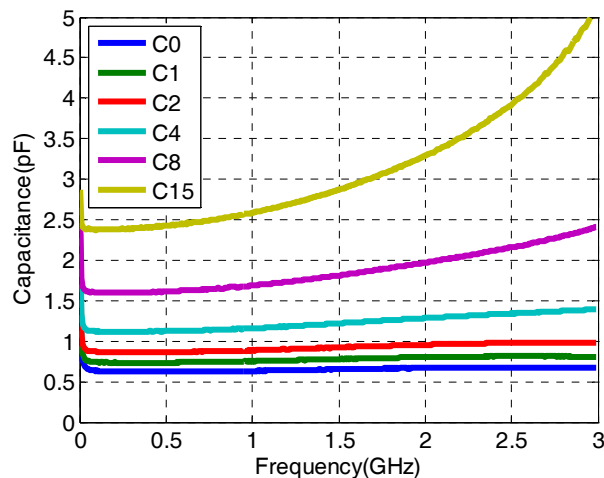


Figure 8. Measured Shunt C vs Frequency (major states)

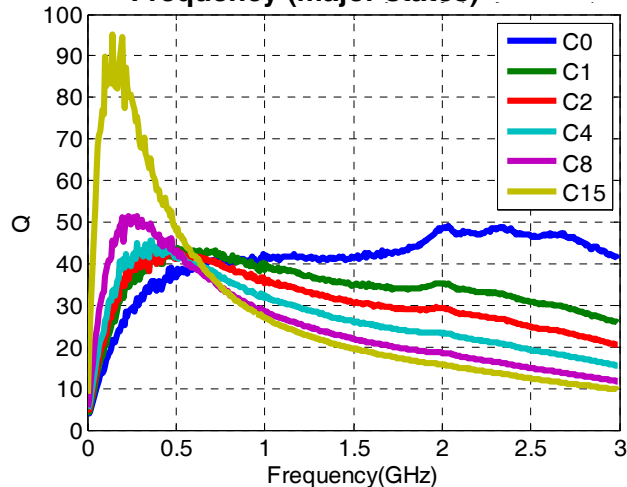
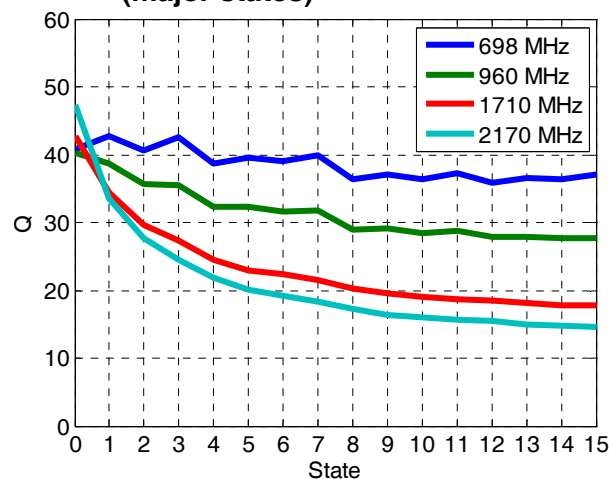


Figure 9. Measured Series S₂₁ vs Frequency (major states)



Serial Interface Operation and Sharing

The PE623090 is controlled by a three wire SPI-compatible interface with enable active high. As shown in *Figure 10*, the serial master initiates the start of a telegram by driving the SEN (Serial Enable) line high. Each bit of the 8-bit telegram (MSB first in) is clocked in on the rising edge of SCL (Serial Clock), as shown in *Table 5* and *Figure 10*. Transitions on SDA (Serial Data) are allowed on the falling edge of SCL. The DTC activates the data on the falling edge of SEN. The DTC does not count how many bits are clocked and only maintains the last 8 bits it received.

More than 1 DTC can be controlled by one interface by utilizing a dedicated enable (SEN) line for each DTC. SDA, SCL, and V_{DD} lines may be shared as shown in *Figure 11*. Dedicated SEN lines act as a chip select such that each DTC will only respond to serial transactions intended for them. This makes each DTC change states sequentially as they are programmed.

Alternatively, a dedicated SDA line with common SEN can be used. This allows all DTCs to change states simultaneously, but requires all DTCs to be programmed even if the state is not changed.

Figure 10. Serial Interface Timing Diagram

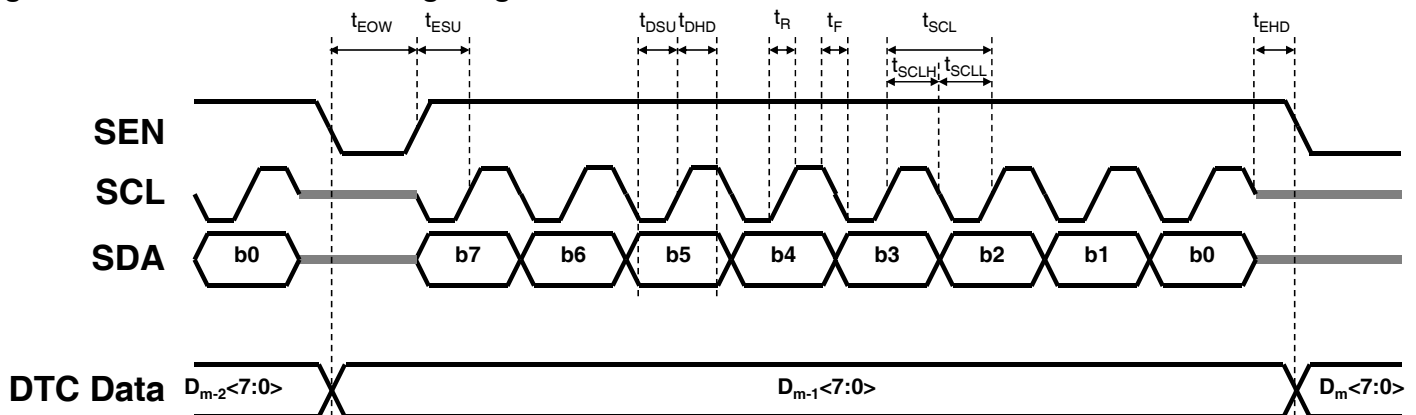


Table 5. 8-Bit Serial Programming Register Map

| b7 | b6 | b5 | b4 | b3 | b2 | b1 | b0 |
|----------------|----------------|------------------|----|----|----|----|----|
| 0 ¹ | 0 ¹ | STB ² | d4 | d3 | d2 | d1 | d0 |

MSB (first in)

LSB (last in)

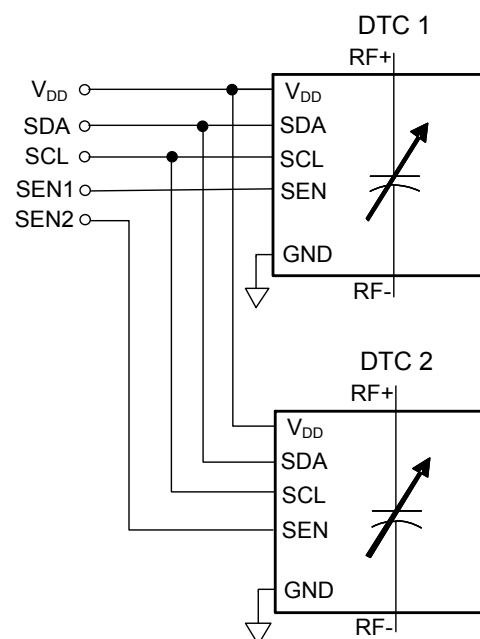
Notes: 1. These bits are reserved and must be written to 0 for proper operation
 2. The DTC is active when low (set to 0) and in low-current stand-by mode when high (set to 1)

Table 6. Serial Interface Timing Characteristics

$V_{DD} = 2.75V$, $-40\text{ }^{\circ}\text{C} < T_A < +85\text{ }^{\circ}\text{C}$, unless otherwise specified

| Symbol | Parameter | Min | Max | Unit |
|------------|-------------------------------------|------|-----|------|
| t_{SCL} | Serial Clock Period | 38.4 | | ns |
| t_{SCLL} | SCL Low Time | 13.2 | | ns |
| t_{SCLH} | SCL High Time | 13.2 | | ns |
| t_R | SCL, SDA, SEN Rise Time | | 6.5 | ns |
| t_F | SCL, SDA, SEN Fall Time | | 6.5 | ns |
| t_{ESU} | SEN rising edge to SCL rising edge | 19.2 | | ns |
| t_{EHD} | SCL rising edge to SEN falling edge | 19.2 | | ns |
| t_{DSU} | SDA valid to SCL rising edge | 13.2 | | ns |
| t_{DHD} | SDA valid after SCL rising edge | 13.2 | | ns |
| t_{EOW} | SEN falling edge to SEN rising edge | 38.4 | | ns |

Figure 11. Recommended Bus Sharing



Equivalent Circuit Model Description

The DTC Equivalent Circuit Model includes all parasitic elements and is accurate in both Series and Shunt configurations, reflecting physical circuit behavior accurately and providing very close correlation to measured data. It can easily be used in circuit simulation programs.

For V_P and V_M max operating limits, refer to Table 3.

Figure 12. Equivalent Circuit Model Schematic

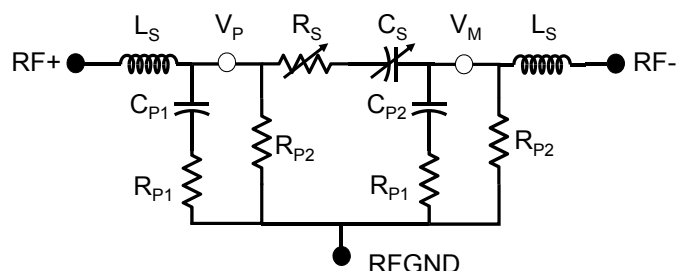


Table 7. Equivalent Circuit Model Parameters

| Variable | Equation (state = 0, 1, 2...15) | Unit |
|----------|---|----------|
| C_S | $0.127 * \text{state} + 0.20$ | pF |
| R_S | $20 / (\text{state} + 20 / (\text{state} + 0.7)) + 0.7$ | Ω |
| R_{P1} | $10 + 4 * \text{state}$ | Ω |
| R_{P2} | $40000 + 10 * \text{state}^3$ | Ω |
| C_{P1} | $-0.01 * \text{state} + 0.40$ | pF |
| C_{P2} | $0.0133 * \text{state} + 0.45$ | pF |
| L_S | 0.35 | nH |

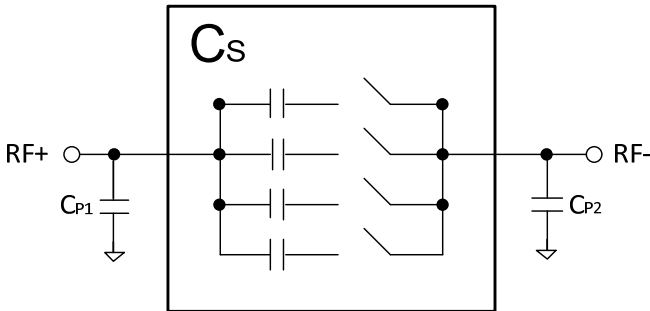
Table 8. Equivalent Circuit Data

| State | | | Effective Capacitance | | Equivalent Circuit Model Parameters | | | | | |
|-------|------|-----|-----------------------|------------|-------------------------------------|--------------------|---------------|---------------|-----------------------|------------------------|
| Hex | Bin | Dec | Series [pF] | Shunt [pF] | C_S [pF] | R_S [Ω] | C_{P1} [pF] | C_{P2} [pF] | R_{P1} [Ω] | R_{P2} [k Ω] |
| 0x00 | 0000 | 0 | 0.20 | 0.60 | 0.20 | 1.40 | 0.40 | 0.45 | 10.0 | 40.0 |
| 0x01 | 0001 | 1 | 0.33 | 0.72 | 0.33 | 2.27 | 0.39 | 0.46 | 14.0 | 40.0 |
| 0x02 | 0010 | 2 | 0.45 | 0.83 | 0.45 | 2.83 | 0.38 | 0.48 | 18.0 | 40.1 |
| 0x03 | 0011 | 3 | 0.58 | 0.95 | 0.58 | 3.08 | 0.37 | 0.49 | 22.0 | 40.3 |
| 0x04 | 0100 | 4 | 0.71 | 1.07 | 0.71 | 3.12 | 0.36 | 0.50 | 26.0 | 40.6 |
| 0x05 | 0101 | 5 | 0.83 | 1.18 | 0.83 | 3.05 | 0.35 | 0.52 | 30.0 | 41.3 |
| 0x06 | 0110 | 6 | 0.96 | 1.30 | 0.96 | 2.93 | 0.34 | 0.53 | 34.0 | 42.2 |
| 0x07 | 0111 | 7 | 1.09 | 1.42 | 1.09 | 2.78 | 0.33 | 0.54 | 38.0 | 43.4 |
| 0x08 | 1000 | 8 | 1.21 | 1.53 | 1.21 | 2.64 | 0.32 | 0.56 | 42.0 | 45.1 |
| 0x09 | 1001 | 9 | 1.34 | 1.65 | 1.34 | 2.51 | 0.31 | 0.57 | 46.0 | 47.3 |
| 0x0A | 1010 | 10 | 1.47 | 1.77 | 1.47 | 2.39 | 0.30 | 0.58 | 50.0 | 50.0 |
| 0x0B | 1011 | 11 | 1.59 | 1.88 | 1.59 | 2.27 | 0.29 | 0.60 | 54.0 | 53.3 |
| 0x0C | 1100 | 12 | 1.72 | 2.00 | 1.72 | 2.17 | 0.28 | 0.61 | 58.0 | 57.3 |
| 0x0D | 1101 | 13 | 1.84 | 2.11 | 1.84 | 2.08 | 0.27 | 0.62 | 62.0 | 62.0 |
| 0x0E | 1110 | 14 | 1.97 | 2.23 | 1.97 | 2.00 | 0.26 | 0.64 | 66.0 | 67.4 |
| 0x0F | 1111 | 15 | 2.10 | 2.35 | 2.10 | 1.93 | 0.25 | 0.65 | 70.0 | 73.8 |

Series Operation

In Series configuration, the effective capacitance between RF+ and RF- ports is represented by C_s and tuning ratio as C_{Smax}/C_{Smin} .

Figure 13. Effective Capacitance Diagram



Shunt Configuration (looking into RF+ when RF- is grounded) will have higher total capacitance at RF+ due to parallel combination of C_s with parasitic capacitance C_{P1} ($C_s + C_{P1}$), as demonstrated in Figure 14 and Table 9.

Figure 14. Typical Capacitance vs. State

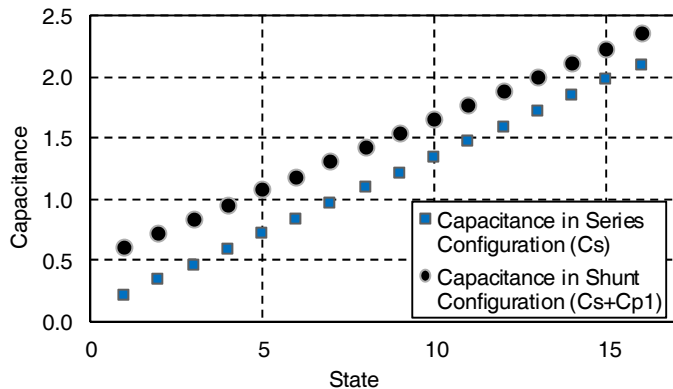


Table 9. Effective Capacitance Summary

| Configuration | Effective Capacitance | C_{min} (state 0) | C_{max} (state 31) | Tuning Ratio |
|---------------------|-----------------------|---------------------|----------------------|--------------|
| Series (RF+ to RF-) | C_s | 0.20 | 2.10 | 10.5:1 |
| Shunt (RF+ to GND) | $C_s + C_{P1}$ | 0.60 | 2.35 | 3.9:1 |

S_{11} and S_{21} for series configuration is illustrated in Figures 15 and 16. S_{21} includes mismatch and dissipative losses and is not indicative of tuning network loss. Equivalent Circuit Model can be used for simulation of tuning network loss.

Figure 15. Measured Series S_{11}/S_{22} (major states)

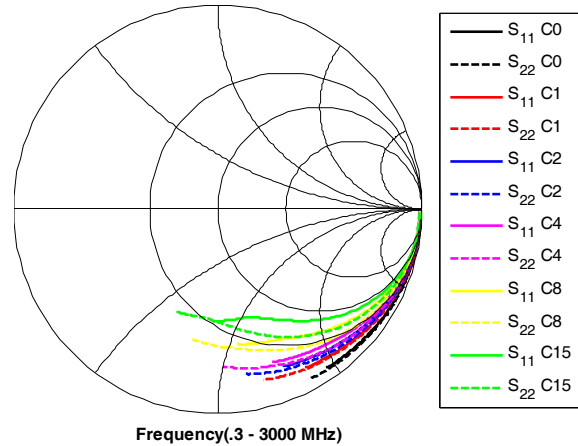
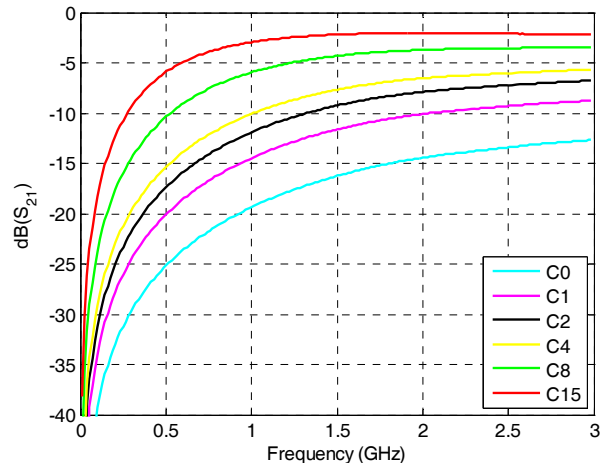


Figure 16. Measured Series S_{21} vs. Frequency (major states)



When the DTC is used as a part of a reactive network, impedance transformation may cause the internal RF voltages (V_P and V_M in Figure 12) to exceed peak operating RF voltage. The complete RF circuit must be simulated using actual input power and load conditions to ensure neither V_P nor V_M exceeds 30 Vpk.

Evaluation Board

The 101-0675 Evaluation Board (EVB) was designed for accurate measurement of the DTC impedance and loss. Two configurations are available: 1 Port Shunt (J3) and 2 Port Shunt (J4, J5). Three calibration standards are provided. The open (J2) and short (J1) standards (104 ps delay) are used for performing port extensions and accounting for electrical length and transmission line loss. The Thru (J9, J10) standard can be used to estimate PCB transmission line losses for scalar de-embedding.

The board consists of a 4 layer stack with 2 outer layers made of Rogers 4350B ($\epsilon_r = 3.48$) and 2 inner layers of FR4 ($\epsilon_r = 4.80$). The total thickness of this board is 62 mils (1.57 mm). The inner layers provide a ground plane for the transmission lines. Each transmission line is designed using a coplanar waveguide with ground plane (CPWG) model using a trace width of 32 mils (0.813 mm), gap of 15 mils (0.381 mm), and a metal thickness of 1.4 mils (0.051 mm).

Figure 17. Evaluation Board

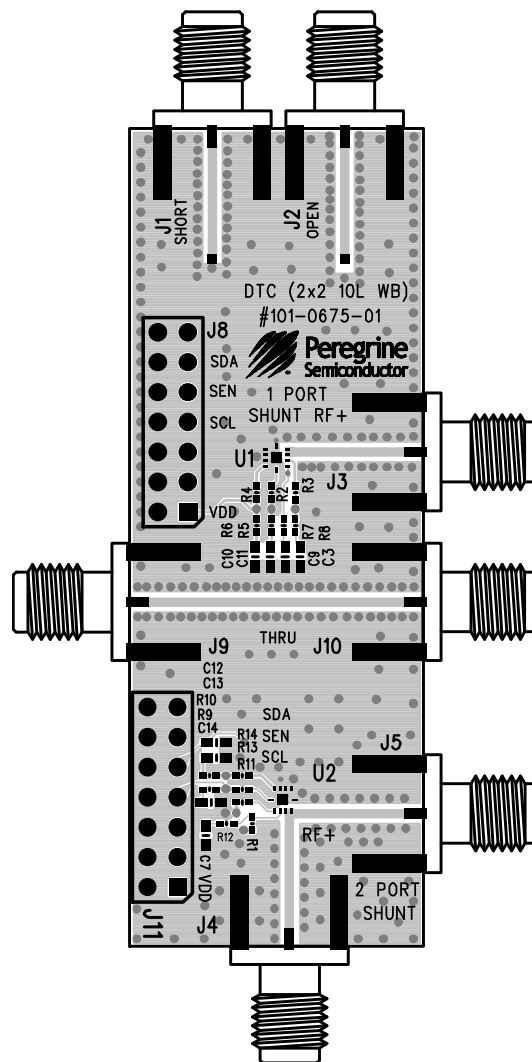


Figure 18. Package Drawing
10-lead 2 x 2 x 0.55 mm

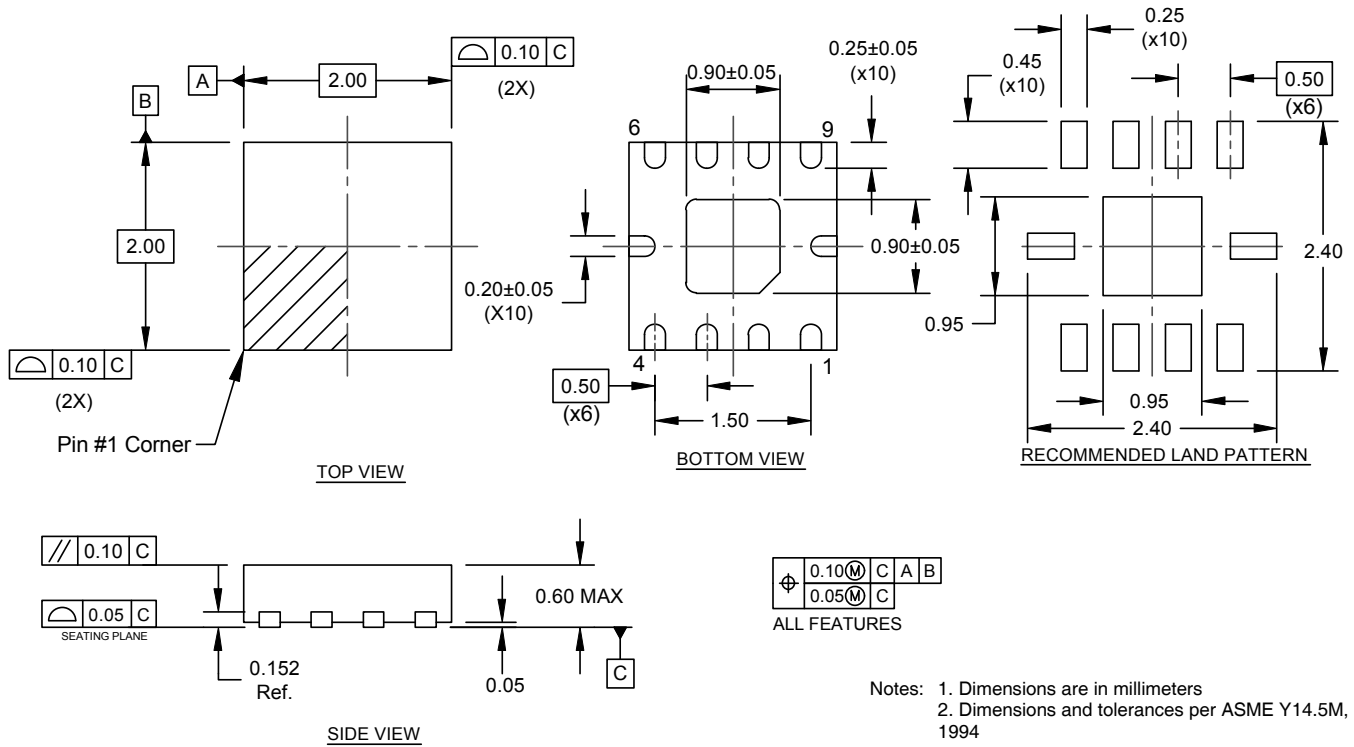
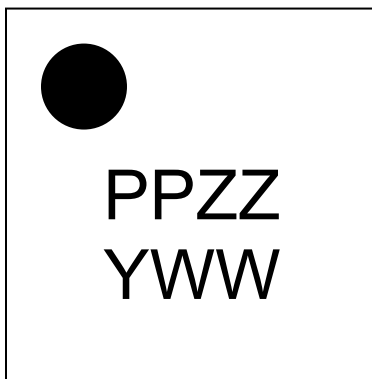


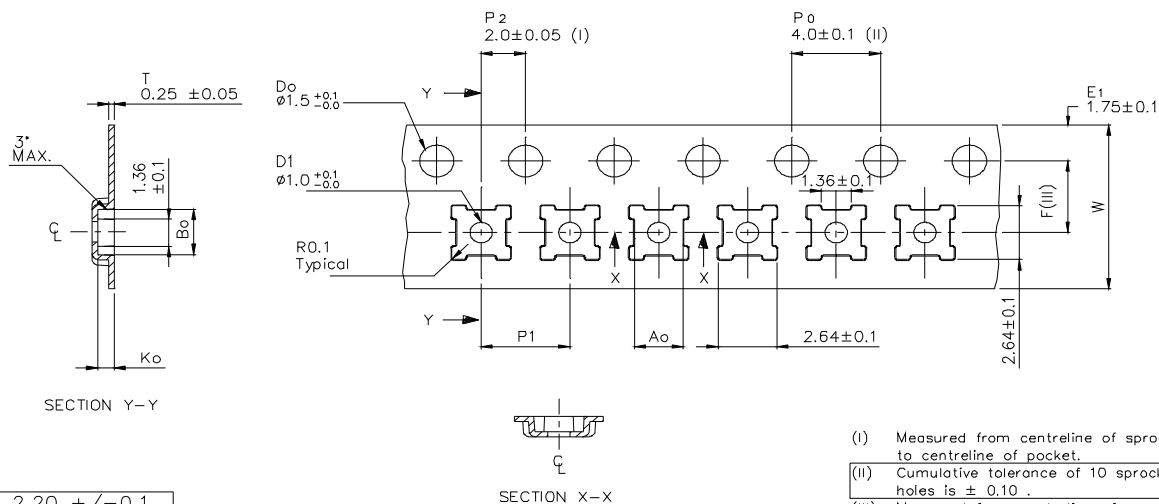
Figure 19. Marking Specifications



| Marking Spec Symbol | Package Marking | Definition |
|---------------------|-----------------|--|
| PP | DF* | Part number marking for PE623090 |
| ZZ | 00-99 | Last two digits of lot code |
| Y | 0-9 | Last digit of year, starting from 2009 (0 for 2010, 1 for 2011, etc) |
| WW | 01-53 | Work week |

Note: (PP), the package marking specific to the PE623090, is shown in the figure instead of the standard Peregrine package marking symbol (P)

Figure 20. Tape and Reel Specifications
10-lead 2 x 2 x 0.55 mm



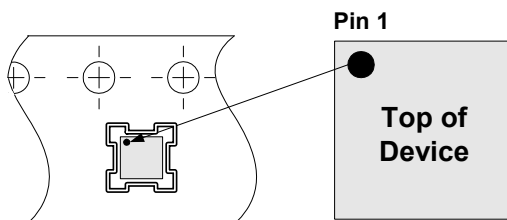
| | |
|----|--------------|
| Ao | 2.20 +/−0.1 |
| B0 | 2.20 +/−0.1 |
| K0 | 0.75 +/−0.1 |
| F | 3.50 +/−0.05 |
| P1 | 4.00 +/−0.1 |
| W | 8.00 +/−0.3 |

- (I) Measured from centreline of sprocket hole to centreline of pocket.
- (II) Cumulative tolerance of 10 sprocket holes is ± 0.10.
- (III) Measured from centreline of sprocket hole to centreline of pocket.
- (IV) Other material available.

This part shall not contain any banned substance as Sony standard SS-00259

ALL DIMENSIONS IN MILLIMETRES UNLESS OTHERWISE STATED.

-----> Tape Feed Direction ----->



Device Orientation in Tape

Table 10. Ordering Information

| Order Code | Package | Description | Shipping Method |
|----------------|-----------------------------|-------------------------------|-------------------|
| PE623090MLAA-Z | 10-lead QFN 2 x 2 x 0.55 mm | Package Part in Tape and Reel | 3,000 units / T&R |
| EK623090-12 | Evaluation Kit | Evaluation Kit | 1 set / box |

Sales and Contact Information

For sales and contact information please visit www.psemi.com.

Advance Information: The product is in a formative or design stage. The datasheet contains design target specifications for product development. Specifications and features may change in any manner without notice.
Preliminary Specification: The datasheet contains preliminary data. Additional data may be added at a later date. Peregrine reserves the right to change specifications at any time without notice in order to supply the best possible product.
Product Specification: The datasheet contains final data. In the event Peregrine decides to change the specifications, Peregrine will notify customers of the intended changes by issuing a CNF (Customer Notification Form).
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